## Notice of References Cited Application/Control No. 10/550,151 Examiner David M. Naff Applicant(s)/Patent Under Reexamination FRANCE ET AL. Art Unit Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,841,617	01-2005	Jeong et al.	524/845
*	В	US-6,290,729	09-2001	Slepian et al.	623/23.72
*	С	US-6,818,018	11-2004	Sawhney, Amarpreet S.	623/11.11
*	D	US-6,129,761	10-2000	Hubbell, Jeffrey A.	623/23.72
	Е	US-			
	F	US-			
	G	US-			
	Ι	US-			
	-	US-			
	J	US-			
	K	US-			
	┙	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	C					
	V					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.